# transphorm TPH3202L Series—Discontinued

# **600V GaN FET PQFN Series**

# Description

The TPH3202L Series 600V,  $290m\Omega$  Gallium Nitride (GaN) FETs are normally-off devices. They combine state-of-the-art high voltage GaN HEMT and low voltage silicon MOSFET technologies—offering superior reliability and performance.

Transphorm GaN offers improved efficiency over silicon, through lower gate charge, lower crossover loss, and smaller reverse recovery charge.

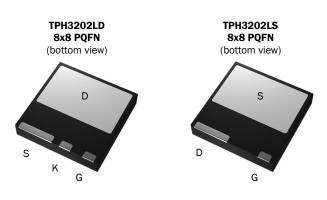
## **Related Literature**

- AN0009: Recommended External Circuitry for GaN FETs
- AN0003: Printed Circuit Board Layout and Probing

## **Product Series and Ordering Information**

Part Number*	Package	Package Configuration
TPH3202LD	8 x 8mm PQFN	Drain
TPH3202LS	8 x 8mm PQFN	Source

\* Add "-TR" suffix for tape and reel; see page 13



#### Features

- JEDEC qualified GaN technology
- Dynamic R<sub>DS(on)eff</sub> production tested
- Robust design, defined by
  - Intrinsic lifetime tests
  - Wide gate safety margin
  - Transient over-voltage capability
- Very low QRR
- Reduced crossover loss
- · RoHS compliant and Halogen-free packaging

#### **Benefits**

- Enables AC-DC bridgeless totem-pole PFC designs
  - Increased power density
  - Reduced system size and weight
  - Overall lower system cost
- Achieves increased efficiency in both hard- and softswitched circuits
- · Easy to drive with commonly-used gate drivers

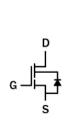
## Applications

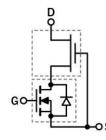
- Datacom
- Broad industrial
- PV inverter
- Servo motor

## **Key Specifications**

V <sub>DSS</sub> (V)	600
V <sub>(TR)DSS</sub> (V)	750
$R_{DS(on)eff}(m\Omega)$ max*	350
Q <sub>RR</sub> (nC) typ	29
Q <sub>G</sub> (nC) typ	6.2

\* Dynamic on-resistance; see Figures 19 and 20





Cascode Schematic Symbol

**Cascode Device Structure** 

# Absolute Maximum Ratings (Tc=25°C unless otherwise stated.)

Symbol	Parameter		Limit Value	Unit	
V <sub>DSS</sub>	Drain to source voltage $(T_J = -5)$	55°C to 175°C)	600		
V <sub>(TR)DSS</sub>	Transient drain to source volta	age <sup>a</sup>	750	V	
V <sub>GSS</sub>	Gate to source voltage		±18		
PD	Maximum power dissipation @	PTc=25°C	65	W	
	Continuous drain current @Tc=25°C b		9	А	
ID	Continuous drain current @Tc=	Continuous drain current @Tc=100°C b		А	
I <sub>DM</sub>	Pulsed drain current (pulse width: 10µs)		35	А	
(di/dt) <sub>RDMC</sub>	Reverse diode di/dt, repetitive °		1200	A/µs	
(di/dt) <sub>RDMT</sub>	Reverse diode di/dt, transient	Reverse diode di/dt, transient <sup>d</sup>		A/µs	
Tc		Case	-55 to +150	°C	
۲J	<ul> <li>Operating temperature</li> </ul>	Junction	-55 to +175	°C	
Ts	Storage temperature	Storage temperature		°C	
T <sub>SOLD</sub>	Soldering peak temperature <sup>e</sup>		260	°C	

Notes:

a. In off-state, spike duty cycle D<0.01, spike duration <1µs

b. For increased stability at high current operation, see Circuit Implementation on page 3

c. Continuous switching operation

d.  $\leq$ 300 pulses per second for a total duration  $\leq$ 20 minutes

e. For 10 sec., 1.6mm from the case

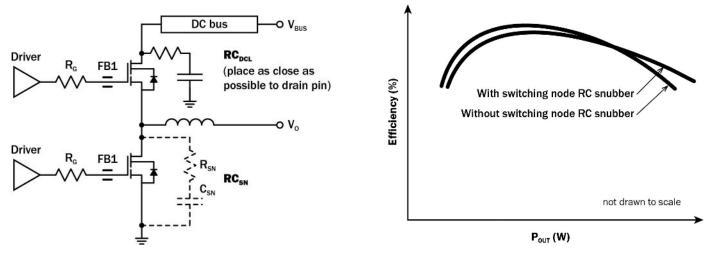
# **Thermal Resistance**

Symbol	Parameter	Typical	Unit
R <sub>ojc</sub>	Junction-to-case	2.3	°C/W
R <sub>ØJA</sub>	Junction-to-ambient <sup>a</sup>	45	°C/W

Notes:

a. Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm<sup>2</sup> copper area and 70µm thickness)

# **Circuit Implementation**



Simplified Half-bridge Schematic

**Efficiency vs Output Power** 

Recommended gate drive: (0V, 8-10V) with  $R_{G(tot)} = 25\Omega$ , where  $R_{G(tot)} = R_{G} + R_{DRIVER}$ 

Gate Ferrite Bead (FB1)	Required DC Link RC Snubber ( $RC_{DCL}$ ) <sup>a</sup>	Recommended Switching Node RC Snubber (RC <sub>SN</sub> ) <sup>b, c</sup>
MMZ1608Y600B	10nF + 8Ω	15pF + 22Ω

Notes:

a.  $RC_{DCL}$  should be placed as close as possible to the drain pin

b. A switching node RC snubber (C, R) is recommended for high switching currents (>70% of IRDMC1 or IRDMC2; see page 5 for IRDMC1 and IRDMC2)

c.  $I_{RDM}$  values can be increased by increasing  $R_G$  and  $C_{SN}$ 

# Electrical Parameters (T\_=25°C unless otherwise stated)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions	
Forward Device Characteristics							
$V_{(BL)DSS}$	Drain-source voltage	600	-	-	V	V <sub>GS</sub> =OV	
$V_{\text{GS}(\text{th})}$	Gate threshold voltage	1.6	2	2.5	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250µA	
р	Drain-source on-resistance <sup>a</sup>	-	290	350	mΩ	V <sub>GS</sub> =8V, I <sub>D</sub> =5.5A	
$R_{DS(on)eff}$	Drain-source on-resistance «	_	670	_		V <sub>GS</sub> =8V, I <sub>D</sub> =5.5A, T <sub>J</sub> =175°C	
l		-	2.5	90		V <sub>DS</sub> =600V, V <sub>GS</sub> =0V	
IDSS	Drain-to-source leakage current	_	8	-	μA	V <sub>DS</sub> =600V, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C	
1	Gate-to-source forward leakage current	-	-	100	nA	V <sub>GS</sub> =18V	
I <sub>GSS</sub>	Gate-to-source reverse leakage current	-	-	-100		V <sub>GS</sub> =-18V	
CISS	Input capacitance	-	760	-			
Coss	Output capacitance	-	28	_	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =400V, <i>f</i> =1MHz	
$C_{\text{RSS}}$	Reverse transfer capacitance	-	3.6	_			
$C_{\text{O}(\text{er})}$	Output capacitance, energy related b	-	40	_	рF	$V_{GS}$ =0V, $V_{DS}$ =0V to 400V	
C <sub>O(tr)</sub>	Output capacitance, time related °	-	63	-	pi		
$Q_{\text{G}}$	Total gate charge	-	6.2	9.3			
Q <sub>GS</sub>	Gate-source charge	-	2.1	-	nC	$V_{DS}$ =400V, $V_{GS}$ =0V to 8V, $I_{D}$ =5.5A	
$Q_{\text{GD}}$	Gate-drain charge	-	2.2	-			
Qoss	Output charge	-	25.3	-	nC	$V_{GS}$ =0V, $V_{DS}$ =0V to 400V	
t <sub>D(on)</sub>	Turn-on delay	-	6.2	-			
t <sub>R</sub>	Rise time	-	4.5	-		V <sub>DS</sub> =400V, V <sub>GS</sub> =0V to 10V,	
$t_{\text{D(off)}}$	Turn-off delay	-	9.7	_	ns	$I_D$ =5.5A, $R_G$ =22 $\Omega$	
t <sub>F</sub>	Fall time	_	5	_	1		

Notes:

a. Dynamic on-resistance; see Figures 19 and 20 for test circuit and conditions

b. Equivalent capacitance to give same stored energy as  $V_{\text{DS}}$  rises from OV to 400V

c. Equivalent capacitance to give same charging time as  $V_{\text{DS}}$  rises from OV to 400V

## Electrical Parameters (T\_=25°C unless otherwise stated)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions	
<b>Reverse Dev</b>	ice Characteristics	1	1	1	1		
ls	Reverse current	_	_	6	A	V <sub>GS</sub> =0V, T <sub>C</sub> =100°C, ≤25% duty cycle	
		_	2.9	-		V <sub>GS</sub> =0V, I <sub>S</sub> =6A	
V <sub>SD</sub>	Reverse voltage <sup>a</sup>	_	4.8	-	v	V <sub>GS</sub> =0V, I <sub>S</sub> =6A, T <sub>J</sub> =175°C	
		_	2.2	-		V <sub>GS</sub> =OV, I <sub>S</sub> =3A	
t <sub>RR</sub>	Reverse recovery time	_	11.5	_	ns	$I_S = 5.5A, V_{DD} = 480V,$ di/dt=15004/us	
Q <sub>RR</sub>	Reverse recovery charge	_	29	-	nC		
(di/dt) <sub>RDMC</sub>	Reverse diode di/dt, repetitive b	_	_	1200	A/µs		
IRDMC1	Reverse diode switching current, repeti- tive (dc) <sup>c, e</sup>	_	_	8	A	Circuit implementation and parameters on page 3	
I <sub>RDMC2</sub>	Reverse diode switching current, repeti- tive (ac) <sup>c, e</sup>	_	_	10	A	Circuit implementation and parameters on page 3	
(di/dt) <sub>RDMT</sub>	Reverse diode di/dt, transient d	_	_	2300	A∕µs		
I <sub>RDMT</sub>	Reverse diode switching current, transient <sup>d,e</sup>	_	_	13	A	Circuit implementation and parameters on page 3	

Notes:

a. Includes dynamic R<sub>DS(on)</sub> effect

b. Continuous switching operation

c. Definitions: dc = dc-to-dc converter topologies; ac = inverter and PFC topologies, 50-60Hz line frequency

d. ≤300 pulses per second for a total duration ≤20 minutes

e.  $\ \ I_{RDM}$  values can be increased by increasing  $R_G$  and  $C_{SN}$  on page 3

# Typical Characteristics (Tc=25 °C unless otherwise stated)

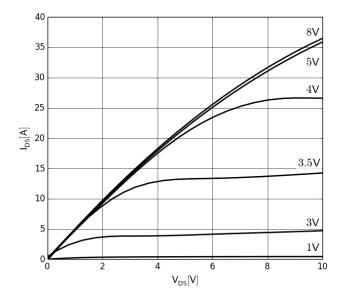
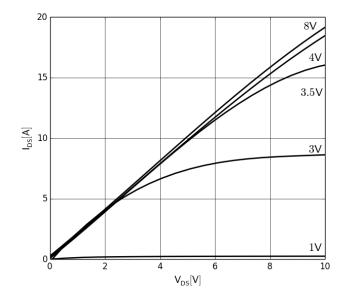
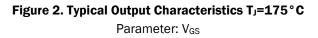
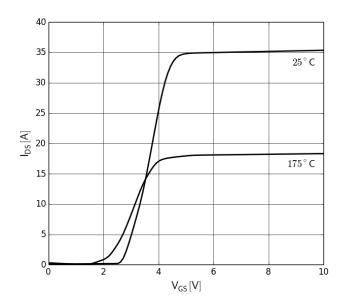
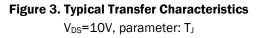


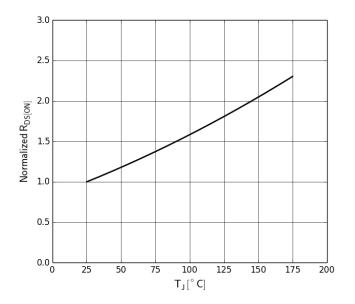
Figure 1. Typical Output Characteristics TJ=25°C Parameter: V<sub>GS</sub>













# Typical Characteristics (Tc=25 $^{\circ}\text{C}$ unless otherwise stated)

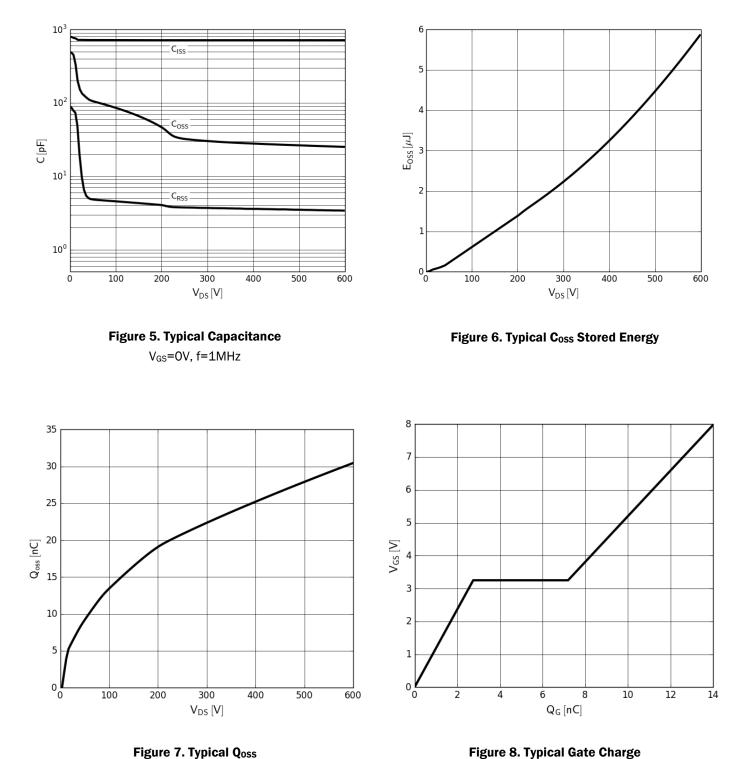
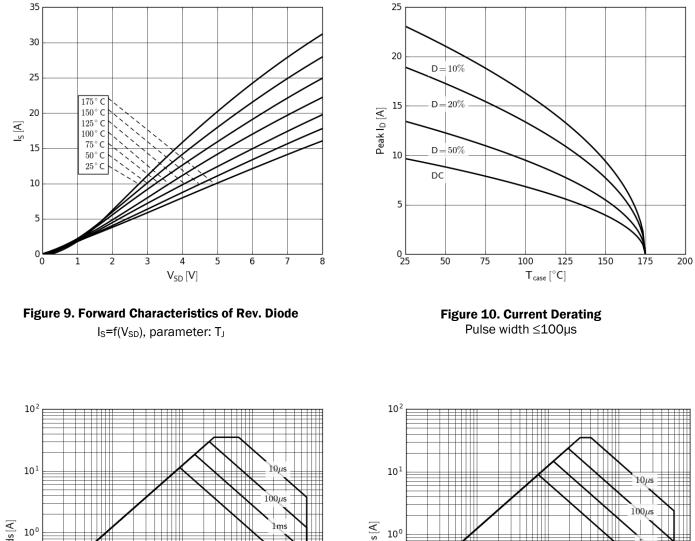
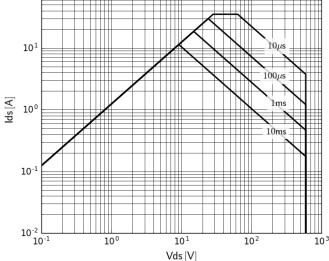
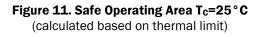


Figure 8. Typical Gate Charge IDS=6A, VDS=400V

# Typical Characteristics (Tc=25 °C unless otherwise stated)







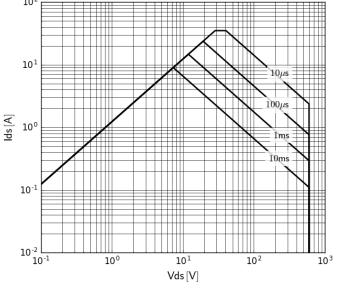
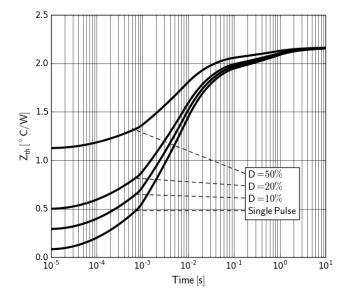


Figure 12. Safe Operating Area Tc=80°C (calculated based on thermal limit)

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# Typical Characteristics (Tc=25 °C unless otherwise stated)





 $B_{a}^{60}$   $B_{a}^{50}$   $B_{$ 

Figure 14. Power Dissipation

# **Test Circuits and Waveforms**

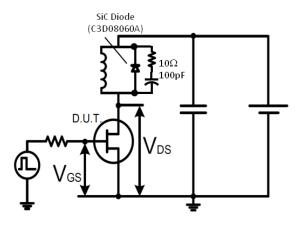


Figure 15. Switching Time Test Circuit (see circuit implementation on page 3 for methods to ensure clean switching)

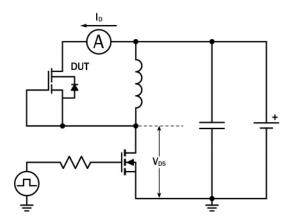


Figure 17. Diode Characteristics Test Circuit

 $R_{SNS}$ 

DUT

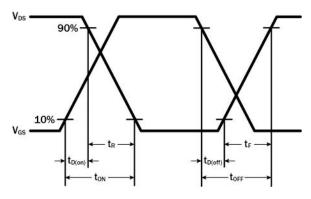
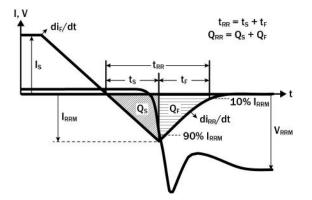
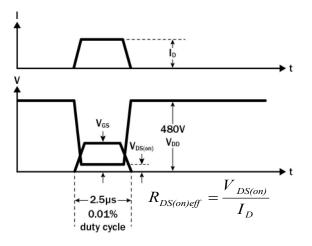


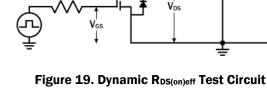
Figure 16. Switching Time Waveform











# **Design Considerations**

The fast switching of GaN devices reduces current-voltage crossover losses and enables high frequency operation while simultaneously achieving high efficiency. However, taking full advantage of the fast switching characteristics of GaN switches requires adherence to specific PCB layout guidelines and probing techniques.

Before evaluating Transphorm GaN devices, see application note <u>Printed Circuit Board Layout and Probing for GaN Power</u> <u>Switches</u>. The table below provides some practical rules that should be followed during the evaluation.

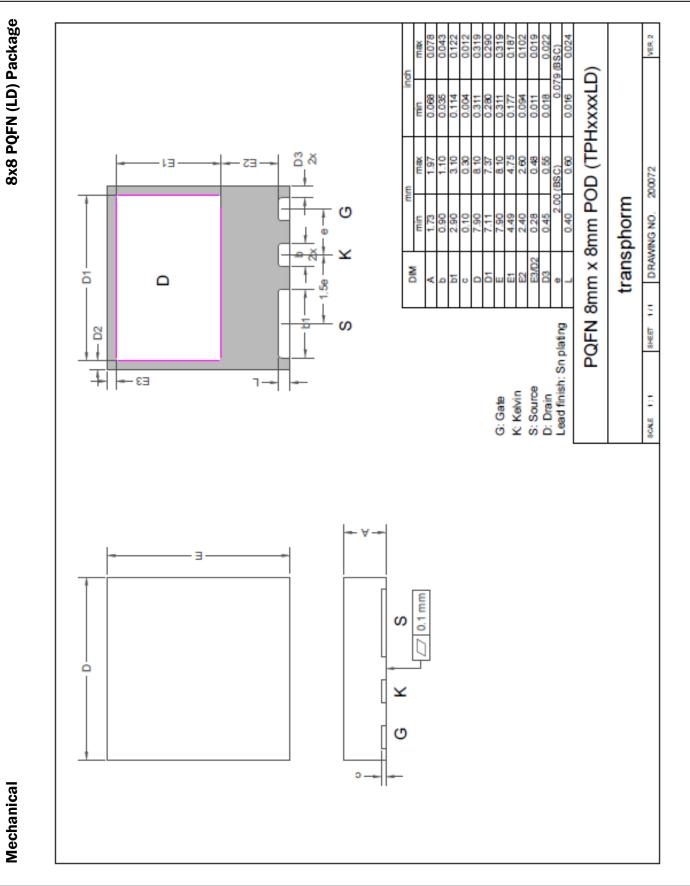
#### When Evaluating Transphorm GaN Devices:

DO	DO NOT
Minimize circuit inductance by keeping traces short, both in the drive and power loop	Twist the pins of TO-220 or TO-247 to accommodate GDS board layout
Minimize lead length of TO-220 and TO-247 package when mounting to the PCB	Use long traces in drive circuit, long lead length of the devices
Use shortest sense loop for probing; attach the probe and its ground connection directly to the test points	Use differential mode probe or probe ground clip with long wire
See AN0003: Printed Circuit Board Layout and Probing	

## **GaN Design Resources**

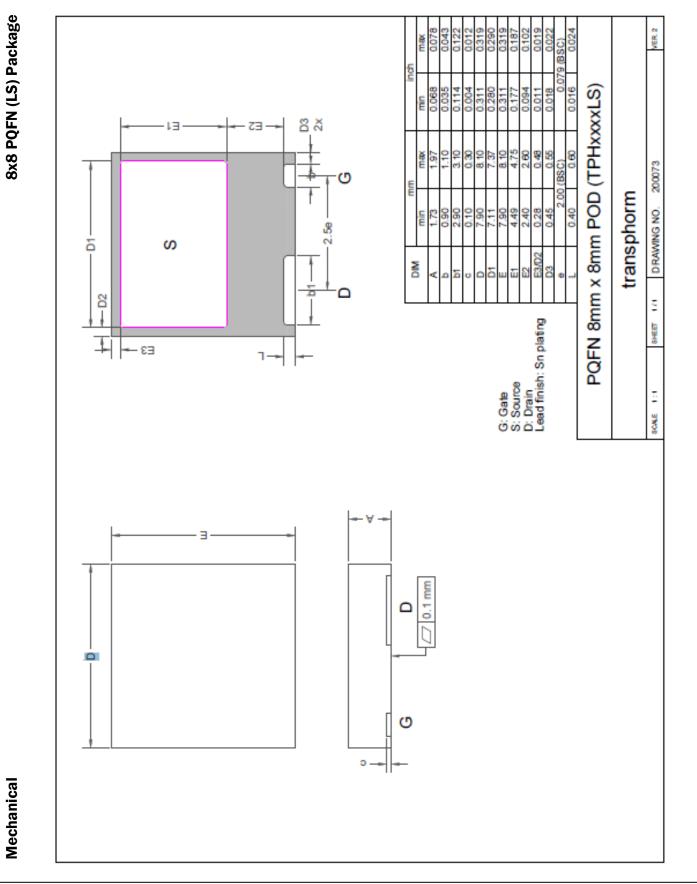
The complete technical library of GaN design tools can be found at transphormusa.com/design:

- Reference designs
- Evaluation kits
- Application notes
- Design guides
- Simulation models
- Technical papers and presentations



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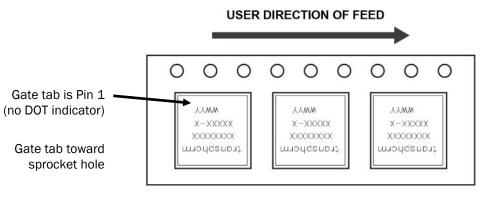


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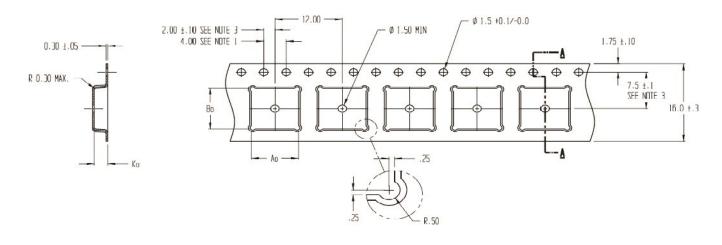
## **PQFN Tape and Reel Information**

#### **Product Orientation**



- Leader empty pockets: 400mm/15.75" min •
- Trailer empty pickets: 160mm/6.3" min
- Quantity per reel: 500 pcs

#### **Carrier Tape Dimension**



Ao = 8.40 Bo = 8.40 Ko = 2.40

NOTES:

1. 10 SPROCKET HOLE PITCH CUMULATIVE TOLERANCE ±0.2

2. CAMBER IN COMPLIANCE WITH EIA 481 3. POCKET POSITION RELATIVE TO SPROCKET HOLE MEASURED

AS TRUE POSITION OF POCKET, NOT POCKET HOLE

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# **Revision History**

Version	Date	Change(s)
0	11/14/2016	Release L series datasheet
1	3/22/2017	Updated dynamic measurement verbiage
2	11/7/2017	<b>Updated</b> Figures 11 & 12 (pg 7), CV data to 400V values, effective on-resistance symbol to $R_{DS(on)eff}$ to adhere to new JEDEC standards; Added switching current values (pg 2), Circuit Implementation (pg 3), $Q_{OSS}$ value (pg 4), Figures 7 & 8 (pg 6)
3	3/27/2018	Product discontinued